

## Description

The μPD434000 is a 524,288-word by 8-bit static RAM fabricated with advanced silicon-gate technology. CMOS peripheral circuits and N-channel memory cells with thin-film transistor (TFT) loads make the μPD434000 a high-speed device that requires very low power and no clock or refreshing.

Minimum standby power is drawn when  $\overline{CS}$  is high, independent of  $\overline{OE}$  and  $\overline{WE}$ . Data retention is guaranteed at a power supply voltage as low as 2 volts.

The μPD434000 is available in standard 32-pin DIP, SOP, and TSOP plastic packaging.

## Features

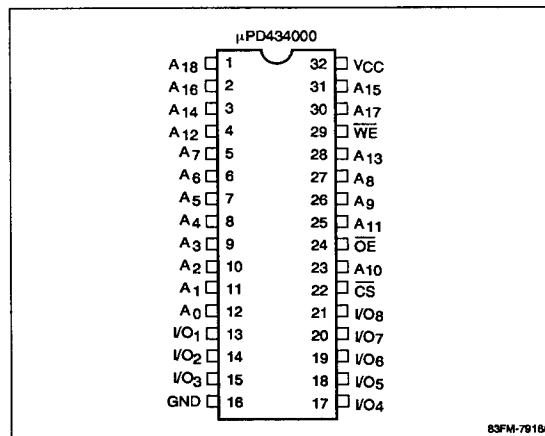
- 524,288-word by 8-bit organization
- Single +5-volt power supply
- Fully static operation—no clock or refreshing
- TTL-compatible inputs and outputs
- Common I/O using three-state outputs
- Chip select ( $\overline{CS}$ ) and output enable ( $\overline{OE}$ ) inputs for easy application
- Data retention current of 0.5 μA typical
- Data retention voltage of 2 V minimum
- Packages: 32-pin plastic DIP, SOP, and TSOP

## Pin Identification

Symbol	Function
A <sub>0</sub> - A <sub>18</sub>	Address inputs
I/O <sub>1</sub> - I/O <sub>8</sub>	Data inputs/outputs
$\overline{CS}$	Chip select
$\overline{OE}$	Output enable
$\overline{WE}$	Write enable
GND	Ground
V <sub>CC</sub>	+ 5-volt power supply
NC	No connection

## Pin Configurations

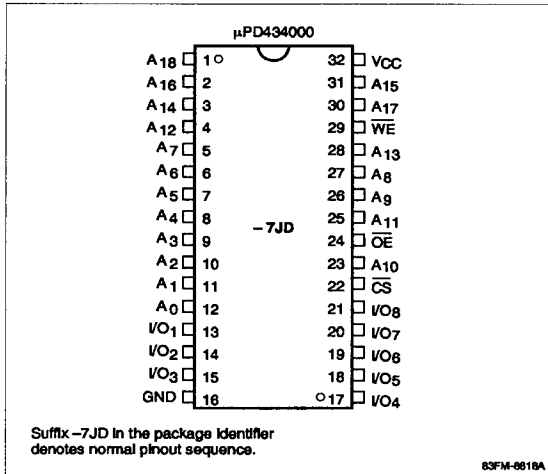
### 32-Pin Plastic DIP or SOP



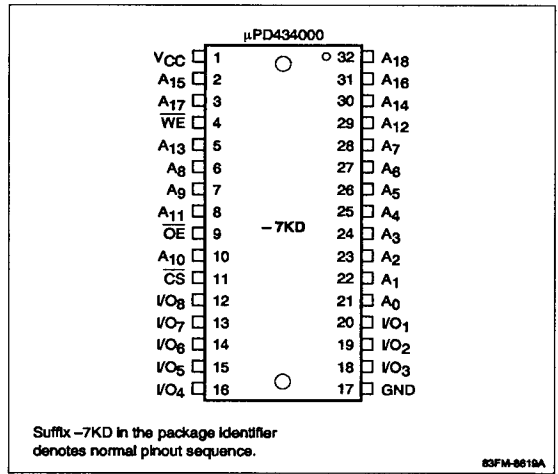
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### Pin Configurations (cont)

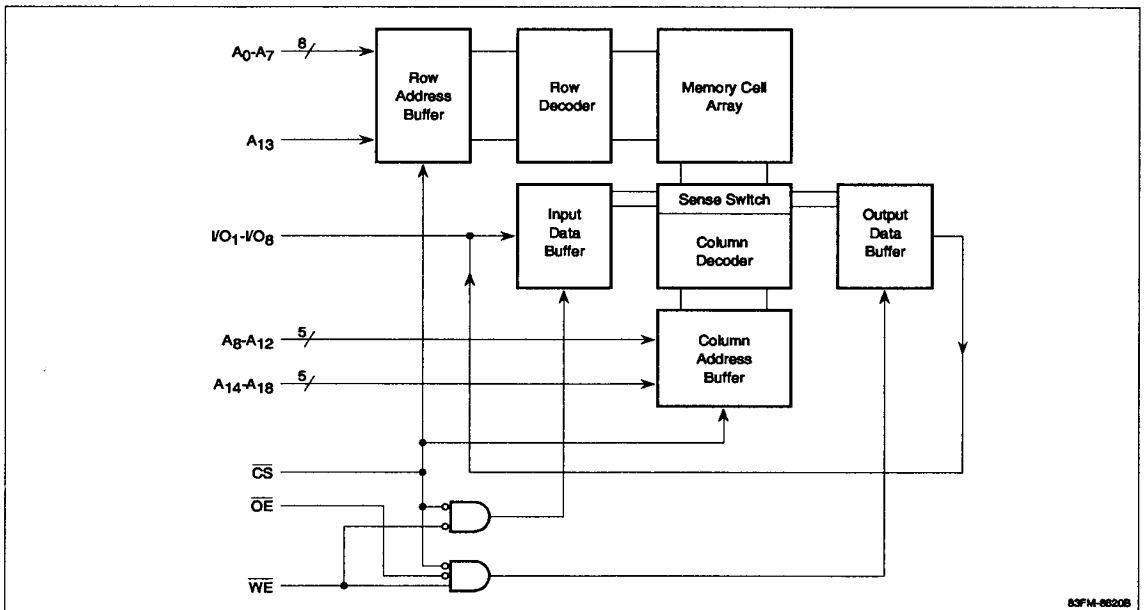
#### 32-Pin Plastic TSOP (Normal Pinouts)



#### 32-Pin Plastic TSOP (Reverse Pinouts)



### Block Diagram



## Ordering Information

Part Number	Access Time (max)	Standby Supply Current	Package
μPD434000CZ-55	55 ns	2 mA	32-pin plastic DIP
CZ-70	70 ns		
CZ-85	85 ns		
CZ-10	100 ns		
μPD434000CZ-55L	55 ns	0.1 mA	
CZ-70L	70 ns		
CZ-85L	85 ns		
CZ-10L	100 ns		
μPD434000CZ-55LL	55 ns	0.05 mA	
CZ-70LL	70 ns		
CZ-85LL	85 ns		
CZ-10LL	100 ns		
μPD434000GW-55	55 ns	2 mA	32-pin plastic SOP
GW-70	70 ns		
GW-85	85 ns		
GW-10	100 ns		
μPD434000GW-55L	55 ns	0.1 mA	
GW-70L	70 ns		
GW-85L	85 ns		
GW-10L	100 ns		
μPD434000GW-55LL	55 ns	0.05 mA	
GW-70LL	70 ns		
GW-85LL	85 ns		
GW-10LL	100 ns		

**μPD434000****Ordering Information (cont)**

<b>Part Number</b>	<b>Access Time (max)</b>	<b>Standby Supply Current</b>	<b>Package</b>
μPD434000G5-55	55 ns	2 mA	32-pin plastic TSOP (normal pinouts)
G5-70	70 ns		
G5-85	85 ns		
G5-10	100 ns		
μPD434000G5-55L	55 ns	0.1 mA	
G5-70L	70 ns		
G5-85L	85 ns		
G5-10L	100 ns		
μPD434000G5-55LL	55 ns	0.05 mA	
G5-70LL	70 ns		
G5-85LL	85 ns		
G5-10LL	100 ns		
μPD434000G5M-55	55 ns	2 mA	32-pin plastic TSOP (reverse pinouts)
G5M-70	70 ns		
G5M-85	85 ns		
G5M-10	100 ns		
μPD434000G5M-55L	55 ns	0.1 mA	
G5M-70L	70 ns		
G5M-85L	85 ns		
G5M-10L	100 ns		
μPD434000G5M-55LL	55 ns	0.05 mA	
G5M-70LL	70 ns		
G5M-85LL	85 ns		
G5M-10LL	100 ns		

### Absolute Maximum Ratings

Supply voltage, $V_{CC}$ (Note 1)	-0.5 to +7.0 V
Input voltage, $V_{IN}$ (Note 1)	-0.5 to $V_{CC}$ + 0.5 V
Output voltage, $V_{IO}$ (Note 1)	-0.5 to $V_{CC}$ + 0.5 V
Operating temperature, $T_{OPR}$	0 to +70°C
Storage temperature, $T_{STG}$	-55 to +125°C
Power dissipation, $P_D$	1.0 W

Exposure to Absolute Maximum Ratings for extended periods may affect device reliability; exceeding the ratings could cause permanent damage. The device should be operated within the limits specified under DC and AC Characteristics.

#### Note:

(1) - 3.0 V minimum (pulse width = 30 ns).

### Capacitance

$T_A = +25^\circ\text{C}$ ;  $f = 1\text{ MHz}$ ;  $V_{IN}$  and  $V_{OUT} = 0\text{ V}$

Parameter †	Symbol	Min	Typ	Max	Unit
Input capacitance	$C_I$			6	pF
Input/output capacitance	$C_{IO}$			10	pF

† Parameter is sampled and not 100% tested.

### DC Characteristics

$T_A = 0\text{ to }+70^\circ\text{C}$ ;  $V_{CC} = +5.0\text{ V} \pm 10\%$

Parameter	Symbol	μPD434000			μPD434000-L			μPD434000-LL			Unit	Test Conditions
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max		
Input leakage current	$I_{LI}$	-1		1	-1		1	-1		1	μA	$V_{IN} = 0\text{ V to }V_{CC}$
I/O leakage current	$I_{LO}$	-1		1	-1		1	-1		1	μA	$V_{IO} = 0\text{ V to }V_{CC}$ ; $\overline{OE} = V_{IH}$ or $\overline{WE} = V_{IL}$ or $\overline{CS} = V_{IH}$
Operating supply current	$I_{CCA2}$			15			15			15	mA	$I_{IO} = 0\text{ mA}$ ; $\overline{CS} = V_{IL}$
	$I_{CCA3}$			15			15			15	mA	$\overline{CS} \leq 0.2\text{ V}$ ; $t_{RC} = 1\text{ }μ\text{s}$ ; $V_{IL} \leq 0.2\text{ V}$ ; $V_{IH} \geq V_{CC} - 0.2\text{ V}$ ; $I_{IO} = 0\text{ mA}$
Standby supply current	$I_{SB}$			5			3			3	mA	$\overline{CS} = V_{IH}$
	$I_{SB1}$		0.02	2		0.002	0.1		0.001	0.05	mA	$\overline{CS} \geq V_{CC} - 0.2\text{ V}$
Output voltage, low	$V_{OL}$			0.4			0.4			0.4	V	$I_{OL} = 2.1\text{ mA}$
Output voltage, high	$V_{OH1}$		2.4			2.4			2.4		V	$I_{OH} = -1.0\text{ mA}$
	$V_{OH2}$		$V_{CC} - 0.5$			$V_{CC} - 0.5$			$V_{CC} - 0.5$		V	$I_{OH} = -0.1\text{ mA}$

### Recommended Operating Conditions

Parameter	Symbol	Min	Typ	Max	Unit
Supply voltage	$V_{CC}$	4.5	5.0	5.5	V
Input voltage, low	$V_{IL}$	-0.3		0.8	V
Input voltage, high	$V_{IH}$	2.2		$V_{CC} + 0.3$	V
Ambient temperature	$T_A$	0		70	°C

#### Note:

(1) - 3.0 V minimum (pulse width = 30 ns).

### Truth Table

Function	$\overline{CS}$	$\overline{OE}$	$\overline{WE}$	I/O	$I_{CC}$
Not selected	H	X	X	High-Z	Standby
$D_{OUT}$ disabled	L	H	H	High-Z	Active
Read	L	L	H	$D_{OUT}$	Active
Write	L	X	L	$D_{IN}$	Active

X = don't care.

**AC Characteristics**

T<sub>A</sub> = 0 to +70°C; V<sub>CC</sub> = +5.0 V ±10%; see figure 1 for ac test conditions.

Parameter	Symbol	-55		-70		-85		-10		Unit	Test Conditions
		Min	Max	Min	Max	Min	Max	Min	Max		
Operating supply current	I <sub>CCA1</sub>		70		65		60		55	mA	$\overline{CS} = V_{IL}; t_{RC} = t_{RC} (min); I_{VO} = 0 \text{ mA}$
Address access time	t <sub>AA</sub>		55		70		85		100	ns	
CS access time	t <sub>ACS</sub>		55		70		85		100	ns	
Address setup time	t <sub>AS</sub>	0		0		0		0		ns	
Address valid to end of write	t <sub>AW</sub>	50		60		70		80		ns	
CS to output in high-Z	t <sub>CHZ</sub>		25		30		30		35	ns	
CS to output in low-Z	t <sub>CLZ</sub>	10		10		10		10		ns	
CS to end of write	t <sub>CW</sub>	50		60		70		80		ns	
Data hold time	t <sub>DH</sub>	0		0		0		0		ns	
Data valid to end of write	t <sub>DW</sub>	30		35		35		40		ns	
Output enable to output valid	t <sub>OE</sub>		30		35		45		50	ns	
Output hold from address change	t <sub>OH</sub>	10		10		10		10		ns	
Output enable to output in high-Z	t <sub>OHZ</sub>		25		30		30		35	ns	
Output enable to output in low-Z	t <sub>OLZ</sub>	5		5		5		5		ns	
Output active from end of write	t <sub>OW</sub>	5		5		5		5		ns	
Read cycle time	t <sub>RC</sub>	55		70		85		100		ns	
Write cycle time	t <sub>WC</sub>	55		70		85		100		ns	
Write enable to output in high-Z	t <sub>WHZ</sub>		25		30		30		35	ns	
Write pulse width	t <sub>WP</sub>	45		55		65		70		ns	
Write recovery time	t <sub>WR</sub>	5		5		5		5		ns	

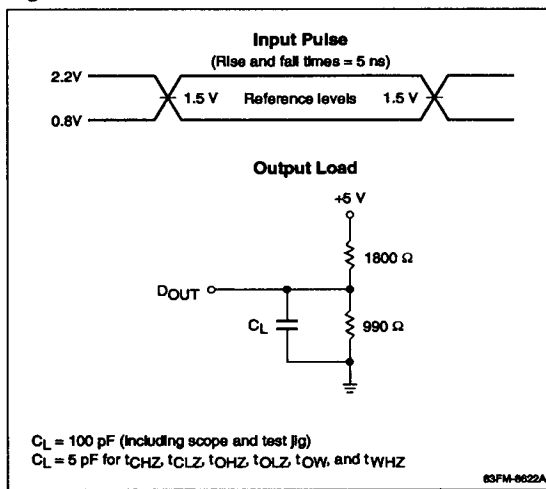
### Low V<sub>CC</sub> Data Retention Characteristics

T<sub>A</sub> = 0 to +70°C; see figure 2 for timing diagram.

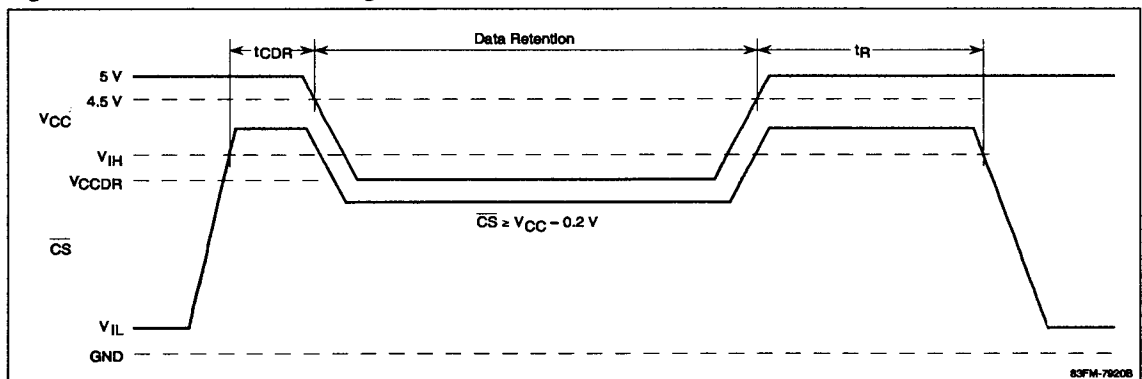
Parameter	Symbol	-L Version			-LL Version			Unit	Test Conditions
		Min	Typ	Max	Min	Typ	Max		
Data retention supply voltage	V <sub>CCDR1</sub>	2		5.5	2		5.5	V	$\overline{CS} \geq V_{CC} - 0.2 V$
Data retention supply current	† I <sub>CCDR1</sub>		1	50		0.5	20	μA	V <sub>CC</sub> = 3.0 V; $\overline{CS} \geq V_{CC} - 0.2 V$
Chip deselection to data retention	t <sub>CDR</sub>	0			0			ns	
Operation recovery time	t <sub>R</sub>	5			5			ms	

† At 0 to 40°C, the maximum for I<sub>CCDR1</sub> is 15 μA for the -L version and 3 μA for the -LL version.

**Figure 1. AC Test Conditions**

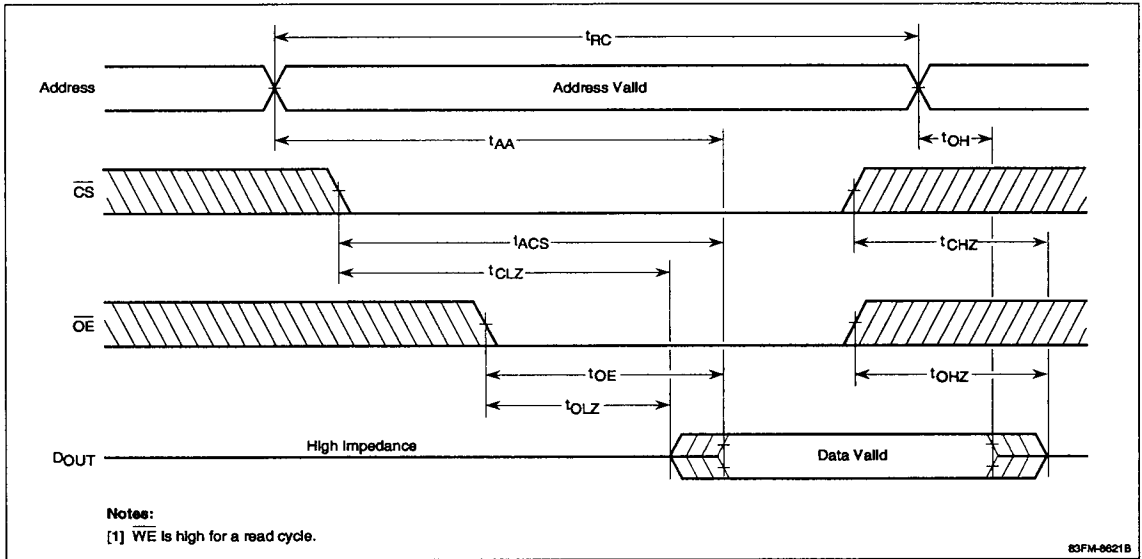


**Figure 2. Data Retention Timing**



Timing Waveforms

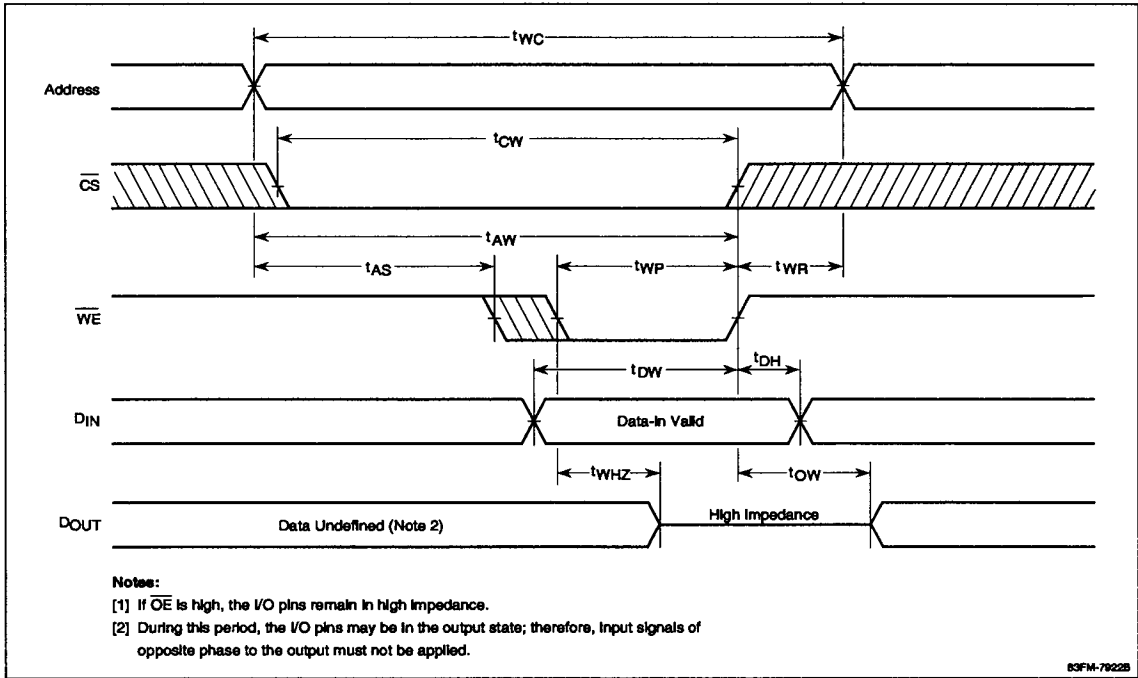
Read Cycle





## Timing Waveforms (cont)

### $\overline{WE}$ -Controlled Write Cycle



Timing Waveforms (cont)

**$\overline{CS}$ -Controlled Write Cycle**

